

<b>Notice of References Cited</b>	Application/Control No. 10/533,171	Applicant(s)/Patent Under Reexamination SEVCIK, JIRI	
	Examiner Gail Verbitsky	Art Unit 2859	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0123892	06-2006	Brekelmans et al.	073/061.76
*	B	US-6,371,147	04-2002	Philippe, Louis	137/6
*	C	US-6,010,243	01-2000	Hessler et al.	374/1
*	D	US-5,988,875	11-1999	Gershfeld et al.	374/10
*	E	US-5,882,115	03-1999	Vander Heyden et al.	374/37
*	F	US-5,759,862	06-1998	Vander Heyden et al.	436/147
*	G	US-4,869,597	09-1989	Christopher, Daniel E.	374/37
*	H	US-4,761,744	08-1988	Singh et al.	700/274
*	I	US-4,720,196	01-1988	Mondeil et al.	374/37
*	J	US-4,306,451	12-1981	Szonntag, Eugene L.	374/36
*	K	US-2,026,180	12-1935	KEITH RAFAEL W	374/37
*	L	US-2005/0190813	09-2005	Schick, Christoph	374/010
*	M	US-3,718,437	02-1973	Paloniemi, Paavo	422/51

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.